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United States Patent [19]

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Burkhart et al.

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[54] ELECTROSTATIC CHUCK WITH IMPROVED SPACING MASK AND WORKPIECE DETECTION DEVICE

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[57] CLAIM

The ornamental design for an electrostatic chuck with improved spacing mask and workpiece detection device, as shown.

[73] Assignee: Applied Materials, Inc., Santa Clara, Calif.

DESCRIPTION

[**] Term: 14 Years

FIG. 1 depicts a top view of the electrostatic chuck with improved spacing mask and workpiece detection device; FIG. 2 depicts an elevation view of the electrostatic chuck when looking up along the y-axis of FIG. 1, the view when looking down along the y-axis, being identical to that of FIG. 2;

[21] Appl. No.: 79,584

FIG. 3 depicts a detailed view of part of a surface and circumferential edge of the electrostatic chuck seen in FIG. 2;

[22] Filed: Nov. 14, 1997

FIG. 4 depicts a bottom view of the electrostatic chuck; FIG. 5 depicts an elevation view of the electrostatic chuck when looking to the left along the x-axis of FIG. 1; and, FIG. 6 depicts an elevation view of the electrostatic chuck when looking to the right along the x-axis of FIG. 1.

[51] LOC (6) Cl. 15-09

[52] U.S. Cl. D15/140

[58] Field of Search D15/140; 118/728; 361/234, 230, 233, 235; 279/128

[56] References Cited

U.S. PATENT DOCUMENTS

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1 Claim, 2 Drawing Sheets

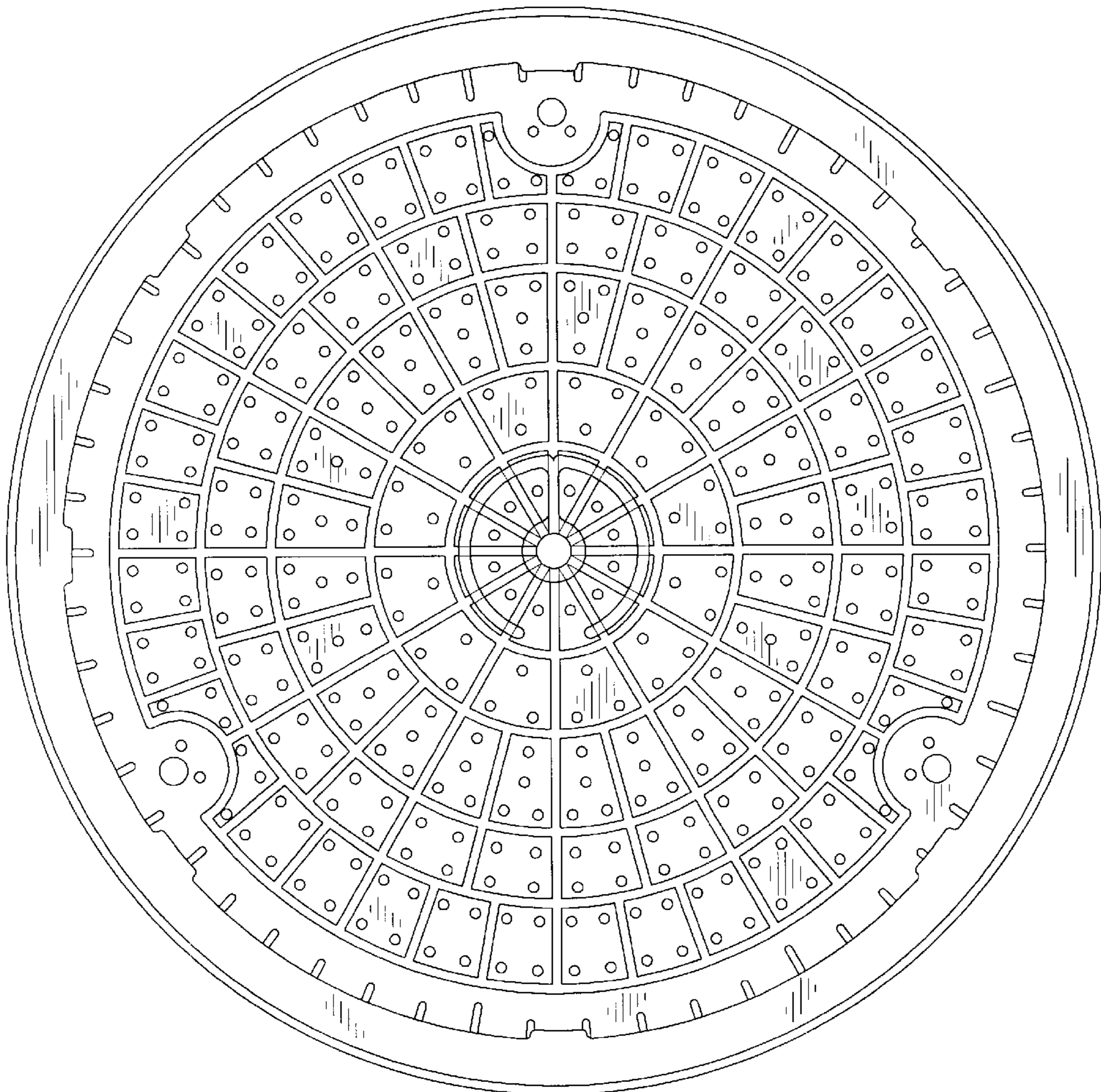


FIG. 1

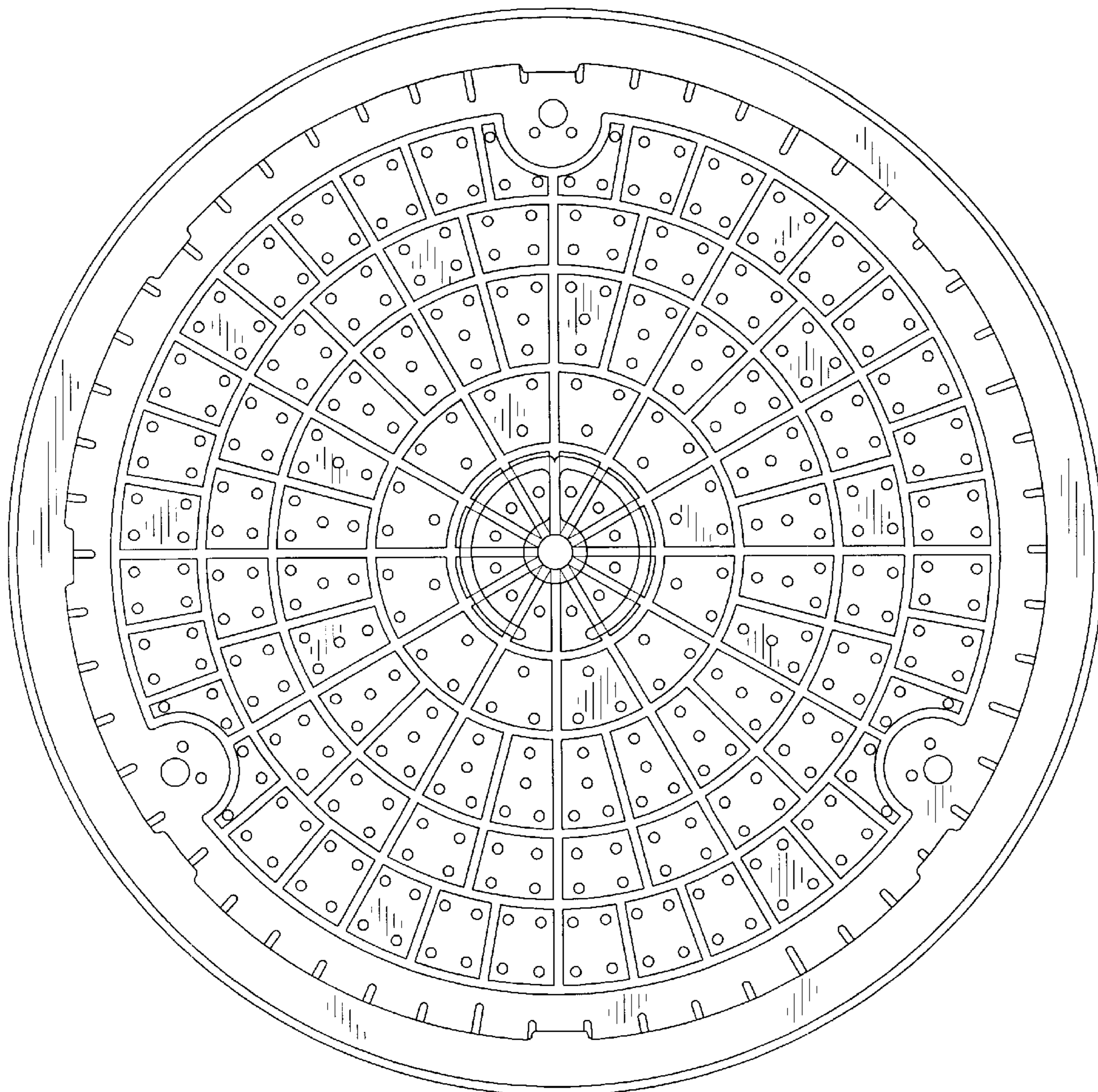


FIG. 2

FIG. 3

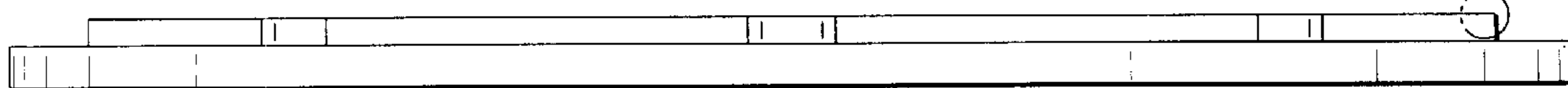


FIG. 3

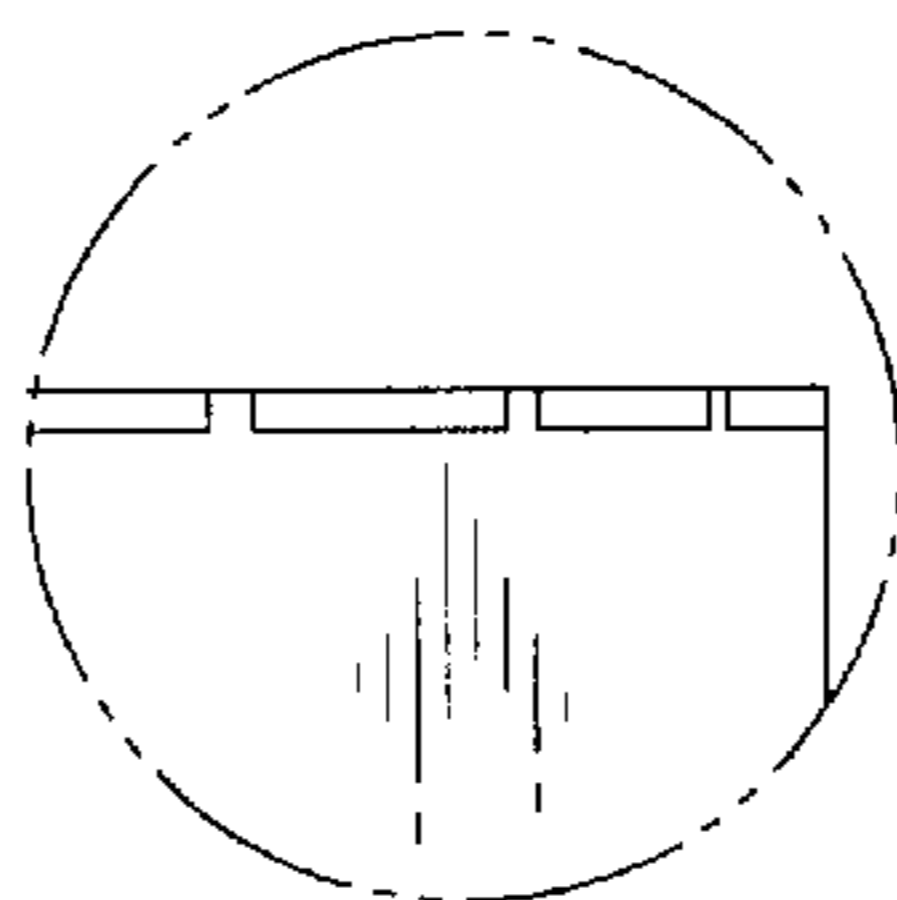


FIG. 4

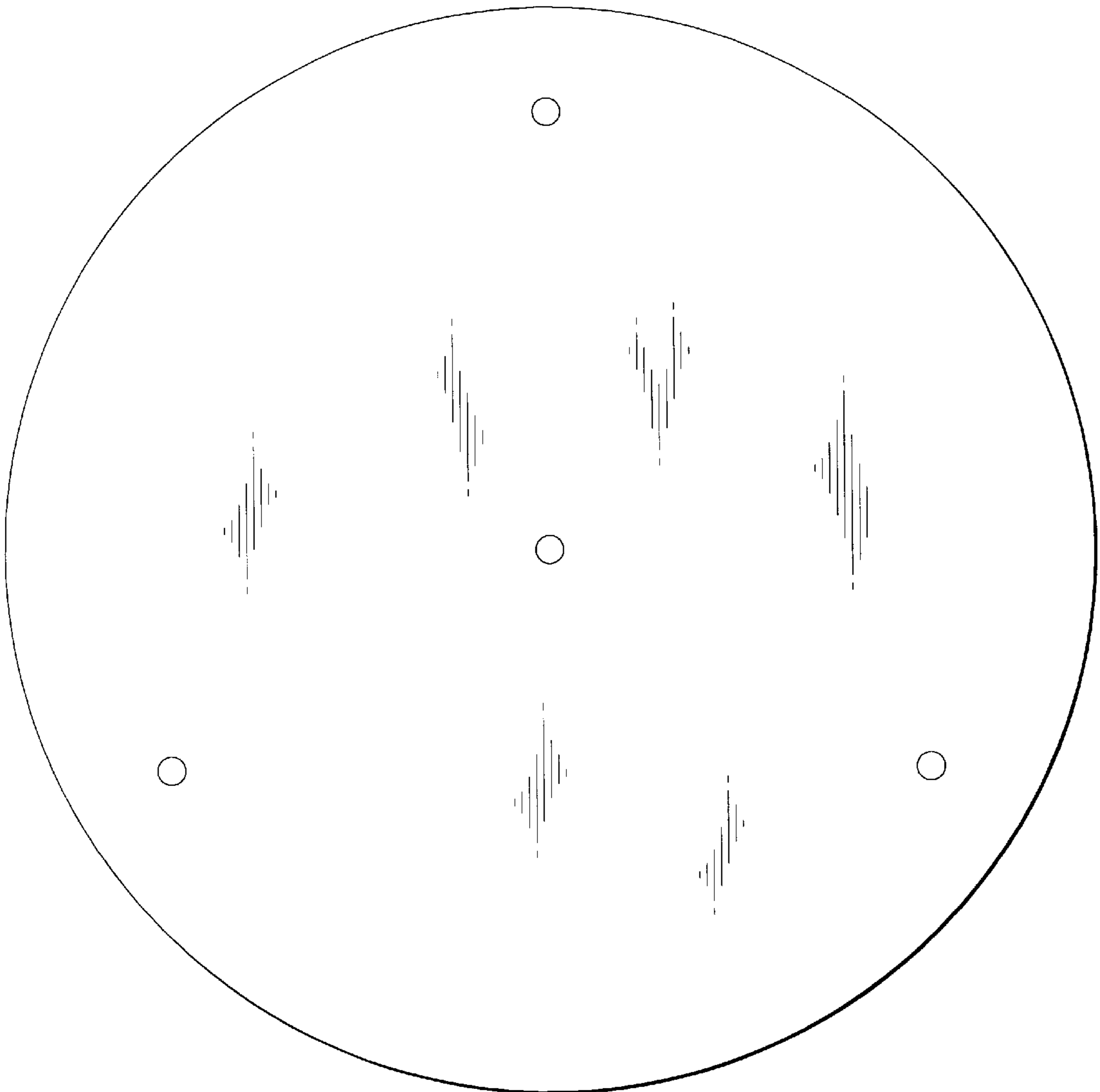


FIG. 5

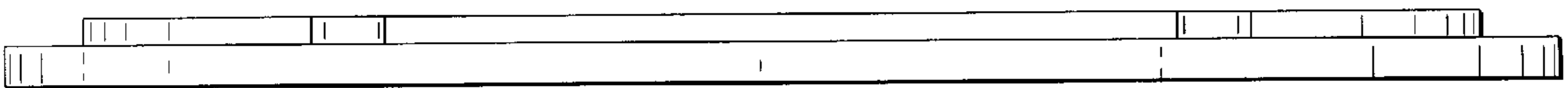


FIG. 6

